Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/044,008	JAIN ET AL.	
Examiner	Art Unit	_
Shin-Hon Chen	2131	

SEARCHED						
Class	Subclass	Date	Examiner			
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INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
713	176, 180	12/19/2006	s.c.		
713	170,168	12/19/2006	S.C.		
713	181	12/19/2006	S.C.		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
DATE	EXMR			
12/19/2006	S.C.			
12/19/2006	S.C.			
	DATE 12/19/2006			